



## DOCUMENT CHANGE REQUEST

DCR number 270 Changes required for: General

Originator: Ron Fidler

Date: 2006/07/24

Date sent: 2006/07/24

Organisation: ESA/ESTEC

Status: IMPLEMENTED

Title: Diode, Silicon, Power Rectifier, Schottky Barrier, based on Type STPS1045

Number: 5106/017

Issue: 1

Other documents affected:

Page:

Total re-write - see below

Paragraph:

Total re-write - see below

Original wording:

Proposed wording:

Total reformat of this Detail Specification as part of the ongoing conversion to the ESCC format.  
See below for summary of changes and attached Issue 2 Draft A of the specification.

Note:

Known support for active procurement against this specification includes the following Manufacturer:  
STM (Variants 01 and 02 supported)

Summary of changes to the current format, layout and content is as follows:

1. Rewording and restructure of various sections and paragraphs of the specification plus other editorial changes based on the layout and editorial content of other Detail Specifications already converted to ESCC format.
2. Deletion of any redundant paragraphs and information, e.g. the mechanical paragraph.
3. Table 1(b) .  $dV/dt$  . rating added and Pulse Condition for .VRRM . rating added.
4. Figure 1 Parameter Derating Requirements - moved to be a note to the Maximum Ratings table.
5. Figures 2 . Dimension .e. corrected from "Typical" to "BSC".
6. Figure 3 . Note added stating that the lid is not connected to any terminal.
7. Para 4.3.2 - Weight requirements moved to Component Type Variants table.



## DOCUMENT CHANGE REQUEST

DCR number 270 Changes required for: General

Date: 2006/07/24

Date sent: 2006/07/24

Originator: Ron Fidler

Organisation: ESA/ESTEC

Status: IMPLEMENTED

8. Requirement for marking of the testing level letter from the ESCC Component Number deleted as per latest ESCC No. 21700.
9. Table 3 (High & Low Temp Electricals) - 100% inspection changed to a sample of 5 components with 0 failures (or 100%) (In line with new generic 5000 Issue 2). New Note added to cover this. Test temperatures with tolerances added.
10. Table 4 - Absolute limits from Table 2 have been added for information.

### Justification:

Justification (see also change details for each item above):

1. Part of the ongoing activity of conversion of cover-sheeted ESA/SCC specifications to the ESCC format.
2. To make the format and presentation consistent with the various other ESCC Detail Specifications already converted to ESCC format (e.g. 54HCMOS and CMOS 4000B series of ESCC IC specifications).
3. To make the content consistent with the ESCC format Generic Specification No.5000 issue 2.
4. To make corrections to several technical errors in the previous issue.

### Attachments:

5106017.pdf, null

### Modifications:

N/A

### Approval signature:

### Date signed:

2006-07-24



Pages 1 to 12

## **DIODES, POWER RECTIFIER, SCHOTTKY BARRIER**

**BASED ON TYPE STPS1045**

**ESCC Detail Specification No. 5106/017**

Issue 2 - Draft A	May 2006
-------------------	----------



Document Custodian: European Space Agency - see <https://escies.org>

**LEGAL DISCLAIMER AND COPYRIGHT**

European Space Agency, Copyright © 2006. All rights reserved.

The European Space Agency disclaims any liability or responsibility, to any person or entity, with respect to any loss or damage caused, or alleged to be caused, directly or indirectly by the use and application of this ESCC publication.

This publication, without the prior permission of the European Space Agency and provided that it is not used for a commercial purpose, may be:

- copied in whole, in any medium, without alteration or modification.
- copied in part, in any medium, provided that the ESCC document identification, comprising the ESCC symbol, document number and document issue, is removed.

**DOCUMENTATION CHANGE NOTICE**

(Refer to <https://escies.org> for ESCC DCR content)

DCR No.	CHANGE DESCRIPTION
TBD	Specification up issued to incorporate editorial and technical changes per DCR.

**TABLE OF CONTENTS**

<b>1.</b>	<b><u>GENERAL</u></b>	<b>5</b>
1.1	Scope	5
1.2	Applicable Documents	5
1.3	Terms, Definitions, Abbreviations, Symbols and Units	5
1.4	The ESCC Component Number and Component Type Variants	5
1.4.1	The ESCC Component Number	5
1.4.2	Component Type Variants	5
1.5	Maximum Ratings	5
1.6	Physical Dimensions and Terminal Identification	7
1.6.1	Surface Mount Package (SMD.5) - 3 Terminal	7
1.7	Functional Diagram	8
1.8	Materials and Finishes	8
<b>2.</b>	<b><u>REQUIREMENTS</u></b>	<b>8</b>
2.1	General	8
2.1.1	Deviations from the Generic Specification	8
2.1.1.1	Deviation from Screening Tests - Chart F3	8
2.1.1.2	Deviations from Qualification and Periodic Tests - Chart F4	8
2.2	Marking	9
2.3	Electrical Measurements at Room, High and Low Temperatures	9
2.3.1	Room Temperature Electrical Measurements	9
2.3.2	High and Low Temperatures Electrical Measurements	9
2.3.3	Notes to Electrical Measurement Tables	10
2.4	Parameter Drift Values	10
2.5	Intermediate and End-Point Electrical Measurements	11
2.6	Power Burn-in Conditions	11
2.7	Operating Life Conditions	11
	APPENDIX 'A'	12

**1. GENERAL**

**1.1 SCOPE**

This specification details the ratings, physical and electrical characteristics and test and inspection data for the component type variants and/or the range of components specified below. It supplements the requirements of, and shall be read in conjunction with, the ESCC Generic Specification listed under Applicable Documents.

**1.2 APPLICABLE DOCUMENTS**

The following documents form part of this specification and shall be read in conjunction with it:

- (a) ESCC Generic Specification No. 5000
- (b) MIL-STD-750, Test Methods and Procedures for Semiconductor Devices

**1.3 TERMS, DEFINITIONS, ABBREVIATIONS, SYMBOLS AND UNITS**

For the purpose of this specification, the terms, definitions, abbreviations, symbols and units specified in ESCC Basic Specification No. 21300 shall apply.

**1.4 THE ESCC COMPONENT NUMBER AND COMPONENT TYPE VARIANTS**

**1.4.1 The ESCC Component Number**

The ESCC Component Number shall be constituted as follows:

Example: 510601701

- Detail Specification Reference: 5106017
- Component Type Variant Number: 01 (as required)

**1.4.2 Component Type Variants**

The component type variants applicable to this specification are as follows:

Variant Number	Based on Type	Case	Description	Terminal Material and Finish	Weight max g
01	STPS1045	SMD.5	Single diode	Q14	2
02	STPS1045	SMD.5	Dual diode, common cathode	Q14	2

The terminal material and finish shall be in accordance with the requirements of ESCC Basic Specification No. 23500.

**1.5 MAXIMUM RATINGS**

The maximum ratings shall not be exceeded at any time during use or storage.

Maximum ratings shall only be exceeded during testing to the extent specified in this specification and when stipulated in Test Methods and Procedures of the ESCC Generic Specification.

Characteristics	Symbols	Maximum Ratings	Unit	Remarks
Forward Surge Current (per Diode)	$I_{FSM}$	200	A	Note 1

Characteristics	Symbols	Maximum Ratings	Unit	Remarks
Repetitive Peak Reverse Voltage	$V_{RRM}$	45	V	Note 2
Repetitive Peak Reverse Current	$I_{RRM}$	1	A	Note 3
Average Output Rectified Current Variants 01 and 02 (per Diode) Variant 02 (per Device)	$I_O$	10 20	A	50% Duty Cycle Notes 4, 7
RMS Forward Current (per Diode)	$I_{F(rms)}$	15	A	
Operating Temperature Range (Case Temperature)	$T_{op}$	-65 to +175	°C	
Junction Temperature	$T_j$	+175	°C	
Storage Temperature Range	$T_{stg}$	-65 to +175	°C	
Soldering Temperature	$T_{sol}$	+245	°C	Note 5
Critical Rate of Rise of Reverse Voltage	$dV/dt$	10000	V/ $\mu$ s	
Thermal Resistance, Junction to Case Variant 01 and 02 (per Diode) Variant 02 (per Device)	$R_{th(j-c)}$	2.8 1.6	°C/W	Notes 6, 7

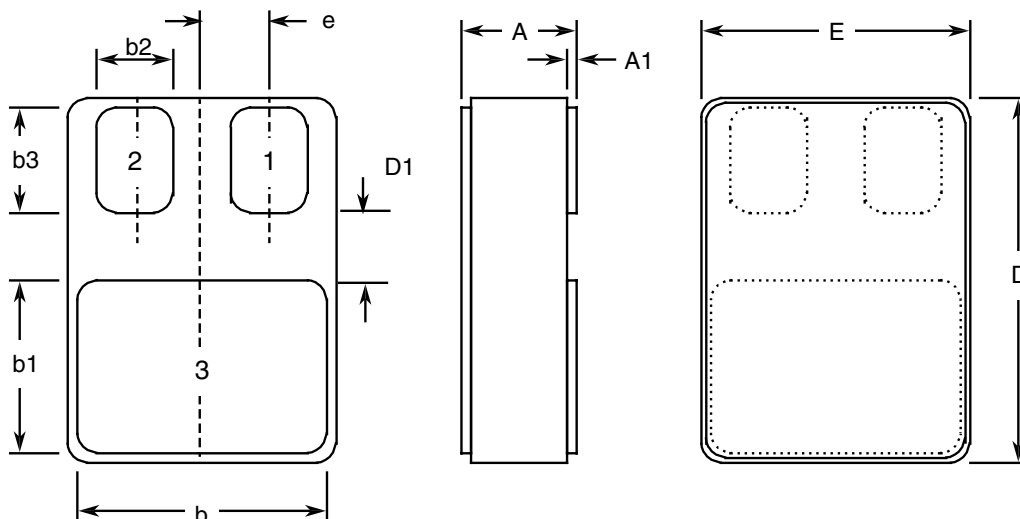
**NOTES:**

1. Sinusoidal pulse of 10ms duration.
2. Pulsed, duration 5ms,  $f = 50\text{Hz}$ .
3. Pulsed, duration  $2\mu\text{s}$ ,  $f = 1\text{kHz}$ .
4. For Variants 01 and 02 per Diode at  $T_{case} > +154^\circ\text{C}$ , or Variant 02 per Device at  $T_{case} > +151^\circ\text{C}$ , derate linearly to 0A at  $+175^\circ\text{C}$ .
5. Duration 5 seconds maximum and the same package shall not be resoldered until 3 minutes have elapsed.
6. Package mounted on infinite heatsink.
7. For Variant 02 the "per Device" ratings apply only when both anode terminals are tied together.



1.6 PHYSICAL DIMENSIONS AND TERMINAL IDENTIFICATION

1.6.1 Surface Mount Package (SMD.5) - 3 Terminal



Symbols	Dimensions mm		Notes
	Min	Max	
A	2.84	3.15	
A1	0.25	0.51	
b	7.13	7.39	
b1	5.58	5.84	
b2	2.28	2.54	2
b3	2.92	3.18	2
D	10.03	10.28	
D1	0.76	-	2
E	7.39	7.64	
e	1.91 BSC		2

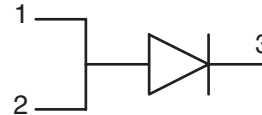
**NOTES:**

1. The terminal identification is specified by the component's geometry. See Functional Diagram for the terminal connections.
2. 2 places.

1.7 FUNCTIONAL DIAGRAM

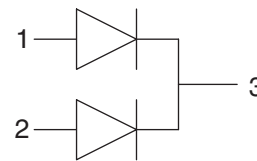
Variant 01

Terminal 1 and 2: Anode  
Terminal 3: Cathode



Variant 02

Terminal 1: Anode a  
Terminal 2: Anode b  
Terminal 3: Common Cathode



**NOTES:**

1. The lid is not connected to any terminal.

1.8 MATERIALS AND FINISHES

Materials and finishes shall be as follows:

- a) Case  
The case shall be hermetically sealed and have a ceramic body with a Kovar lid.
- b) Terminals  
As specified in Component Type Variants.

2. REQUIREMENTS

2.1 GENERAL

The complete requirements for procurement of the components specified herein are as stated in this specification and the ESCC Generic Specification. Permitted deviations from the Generic Specification, applicable to this specification only, are listed below.

Permitted deviations from the Generic Specification and this Detail Specification, formally agreed with specific Manufacturers on the basis that the alternative requirements are equivalent to the ESCC requirement and do not affect the component's reliability, are listed in the appendices attached to this specification.

2.1.1 Deviations from the Generic Specification

2.1.1.1 *Deviation from Screening Tests - Chart F3*

- (a) High Temperature Reverse Bias Burn-in and the subsequent Final Measurements for HTRB shall be omitted.

2.1.1.2 *Deviations from Qualification and Periodic Tests - Chart F4*

- (a) Constant Acceleration is not applicable.

(b) Terminal Strength is not applicable.

2.2 **MARKING**

The marking shall be in accordance with the requirements of ESCC Basic Specification No. 21700 and as follows.

The information to be marked on the component shall be:

- (a) The ESCC qualified components symbol (for ESCC qualified components only).
- (b) The ESCC Component Number.
- (c) Traceability information.

2.3 **ELECTRICAL MEASUREMENTS AT ROOM, HIGH AND LOW TEMPERATURES**

Electrical measurements shall be performed at room, high and low temperatures. Consolidated notes are given after the tables.

2.3.1 **Room Temperature Electrical Measurements**

The measurements shall be performed at  $T_{amb}=+22 \pm 3^{\circ}C$ .

Characteristics	Symbols	MIL-STD-750 Test Method	Test Conditions Note 1	Limits		Units
				Min	Max	
Reverse Current	$I_R$	4016	DC Method $V_R = 45V$	-	100	$\mu A$
Forward Voltage	$V_{F1}$	4011	Pulse Method $I_F=3A$ , Note 2	-	620	mV
	$V_{F2}$	4011	Pulse Method $I_F=10A$ , Note 2	-	750	mV
	$V_{F3}$	4011	Pulse Method $I_F=20A$ , Note 2	-	880	mV
Capacitance	C	4001	$V_R = 5V$ $f = 1MHz$	-	500	pF
Thermal Impedance, Junction to Case	$Z_{th(j-c)}$	3101	$I_H = 15$ to 40A $t_H = 50ms$ $I_M = 50mA$ $t_{md} = 100\mu s$ Note 3	(Calculate $\Delta V_F$ , see Note 4)		$^{\circ}C/W$

2.3.2 **High and Low Temperatures Electrical Measurements**

Characteristics	Symbols	MIL-STD-750 Test Method	Test Conditions Notes 1 and 5	Limits		Units
				Min	Max	
Reverse Current	$I_R$	4016	$T_{case}=+125 (+0 -5)^{\circ}C$ DC Method $V_R = 45V$	-	15	mA

Characteristics	Symbols	MIL-STD-750 Test Method	Test Conditions Notes 1 and 5	Limits		Units
				Min	Max	
Forward Voltage	V <sub>F1</sub>	4011	T <sub>case</sub> =+125 (+0 -5) <sup>o</sup> C Pulse Method I <sub>F</sub> =3A, Note 3	-	570	mV
	V <sub>F2</sub>	4011	T <sub>case</sub> =+125 (+0 -5) <sup>o</sup> C Pulse Method I <sub>F</sub> =10A, Note 3	-	700	mV
			T <sub>case</sub> =-55(+5 -0) <sup>o</sup> C Pulse Method I <sub>F</sub> =10A, Note 3	-	850	
	V <sub>F3</sub>	4011	T <sub>case</sub> =+125 (+0 -5) <sup>o</sup> C Pulse Method I <sub>F</sub> =20A, Note 3	-	800	mV

2.3.3 Notes to Electrical Measurement Tables

1. Measurement per each Diode.
2. Pulse Width ≤ 300μs, Duty Cycle ≤ 2%
3. Performed only during Screening Tests Parameter Drift Values (Initial Measurements), go-no-go.
4. The limits for ΔV<sub>F</sub> shall be defined by the Manufacturer on every lot in accordance with MIL-STD-750 Method 3101 and shall guarantee the R<sub>th(j-c)</sub> limits specified in Maximum Ratings.
5. Read and record measurements shall be performed on a sample of 5 components with 0 failures. Alternatively a 100% inspection may be performed.

2.4 PARAMETER DRIFT VALUES

Unless otherwise specified, the measurements shall be performed at T<sub>amb</sub>=+22 ±3<sup>o</sup>C.  
 The test methods and test conditions shall be as per the corresponding test defined in Room Temperature Electrical Measurements.  
 The drift values (Δ) shall not be exceeded for each characteristic specified. The corresponding absolute limit values for each characteristic shall not be exceeded.

Characteristics	Symbols	Limits			Units
		Drift Value Δ	Absolute		
			Min	Max	
Reverse Current	I <sub>R</sub>	±25 or (1) ±100%	-	100	μA
Forward Voltage	V <sub>F1</sub>	±50	-	620	mV
	V <sub>F3</sub>	±50	-	880	mV

**NOTES:**

1. Whichever is the greater referred to the initial value.

2.5 INTERMEDIATE AND END-POINT ELECTRICAL MEASUREMENTS

Unless otherwise specified, the measurements shall be performed at  $T_{amb}=+22 \pm 3^{\circ}\text{C}$ .

The test methods and test conditions shall be as per the corresponding test defined in Room Temperature Electrical Measurements .

The limit values for each characteristic shall not be exceeded.

Characteristics	Symbols	Limits		Units
		Min	Max	
Reverse Current	$I_R$	-	100	$\mu\text{A}$
Forward Voltage	$V_{F1}$	-	620	mV
	$V_{F2}$	-	750	mV
	$V_{F3}$	-	880	mV

2.6 POWER BURN-IN CONDITIONS

Characteristics	Symbols	Test Conditions	Units
Case Temperature	$T_{case}$	+125	$^{\circ}\text{C}$
Reverse Voltage	$V_R$	36	V

2.7 OPERATING LIFE CONDITIONS

The conditions shall be as specified for Power Burn-in.

**APPENDIX 'A'****AGREED DEVIATIONS FOR STMICROELECTRONICS (F)**

ITEMS AFFECTED	DESCRIPTION OF DEVIATIONS
Deviations from Production Control- Chart F2	Special In-process Control Internal Visual Inspection. Wedge bonds equal to 1.1 wire diameters are acceptable for bonding with a V-Groove tool.